## **MA2J1110G**

## Silicon epitaxial planar type

### For switching circuits

#### ■ Features

- Allowing high-density mounting
- Short reverse recovery time t<sub>rr</sub>
- ullet Small terminal capacitance  $C_t$
- High breakdown voltage:  $V_R = 80 \text{ V}$

## ■ Absolute Maximum Ratings $T_a = 25$ °C

Parameter	Symbol	Rating	Unit
Reverse voltage	$V_R$	80	V
Maximum peak reverse voltage	$V_{RM}$	80	V
Forward current	$I_{F}$	100	mA
Peak forward current	$I_{FM}$	225	mA
Non-repetitive peak forward	$I_{FSM}$	500	mA
surge current *			
Junction temperature	T <sub>j</sub>	150	°C
Storage temperature	$T_{stg}$	-55 to +150	°C

Note) \*: t = 1 s

### Package

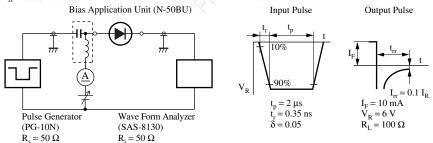
- Code
  - SMini2-F3
- Pin Name
  - 1: Anode 2: Cathode
- Marking Symbol: 1B

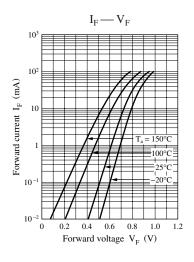
### ■ Electrical Characteristics $T_a = 25$ °C $\pm 3$ °C

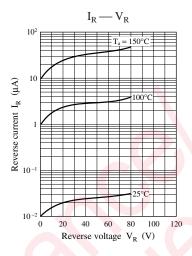
Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Forward voltage	$V_{\mathrm{F}}$	$I_F = 100 \text{ mA}$		0.95	1.20	V
Reverse voltage	$V_R$	$I_R = 100 \mu A$	80			V
Reverse current	$I_R$	V <sub>R</sub> = 75 V			100	nA
Terminal capacitance	C <sub>t</sub>	$V_R = 0 V, f = 1 MHz$		0.6	1.2	pF
Reverse recovery time *	t <sub>rr</sub>	$I_F = 10 \text{ mA}, V_R = 6 \text{ V}$			3	ns
		$I_{rr} = 0.1 I_{R}$ , $R_{L} = 100 \Omega$				

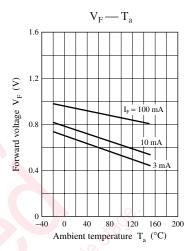
Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7031 measuring methods for diodes.

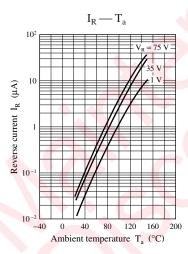
- 2. Absolute frequency of input and output is 100 MHz.
- 3. \*: t<sub>rr</sub> measurement circuit

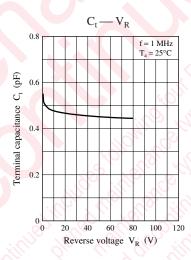


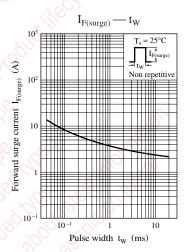






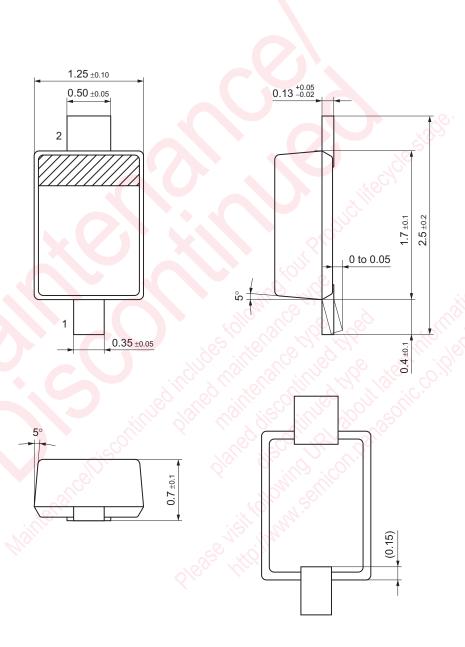






2 SKF00091AED

SMini2-F3 Unit: mm



SKF00091AED 3

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